

Notice of References Cited	Application/Control No. 10/784,334		Applicant(s)/Patent Under Reexamination TRAVIESO ET AL.	
	Examiner Gregory J. Vaughn		Art Unit 2178	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,526,426 B1	02-2003	Lakritz, David	715/536
*	B	US-6,623,529 B1	09-2003	Lakritz, David	715/536
*	C	US-6,980,953 B1	12-2005	Kanevsky et al.	704/235
*	D	US-7,020,601 B1	03-2006	Hummel et al.	704/2
*	E	US-2002/0019839 A1	02-2002	Shiu, P. K.	707/536
*	F	US-2002/0133523 A1	09-2002	Ambler et al.	707/536
*	G	US-2002/0165885 A1	11-2002	Kumhyr et al.	707/536
*	H	US-2003/0115552 A1	06-2003	Jahnke et al.	715/536
*	I	US-2003/0120478 A1	06-2003	Palmquist, Robert	704/3
*	J	US-2003/0140316 A1	07-2003	Lakritz, David	715/536
*	K	US-2005/0283473 A1	12-2005	Rousso et al.	707/005
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.